

<b>LIST OF PRIOR ART CITED BY APPLICANT</b>  <b>(PTO-1449)</b>				ATTY. DOCKET NO. <b>RPL-0006REI</b>		REISSUE OF PATENT NO. <b>6,281,628</b>	
				APPLICANT(S) <b>Tae-Wan CHOI and Seong-Ho KANG</b>			
				FILING DATE <b>8/27/2003</b>		GROUP <b>2886</b>	

  

U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
/RP/	5,155,414	10/13/92	SANO	315	169.4	
/RP/	5,736,815	4/1998	AMEMIYA	313	586	

  

U.S. PATENT APPLICATION PUBLICATIONS						
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

  

U.S. PATENT APPLICATIONS						
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

  

FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
/RP/	63131436 A	06/03/88	JAPAN			X	
	02148645 A	06/07/90	JAPAN			X	
	05250992 A	09/28/93	JAPAN			X	
	04272634 A	09/29/92	JAPAN			X	
	06044907	02/18/94	JAPAN			X	
/RP/	4280289	10/06/92	JAPAN			X	
	09-160525	06/20/97	JAPAN			X	

  

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)	
/RP/	Additional English Translation of 63131436 A
/RP/	Additional English Translation of 02148645 A
/RP/	Additional English Translation of 4280289

  

EXAMINER    /Roy Punnoose/	DATE CONSIDERED    02/19/2008
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.